Abstracts

Computer-Controlled Infrared Microscope for Thermal Analysis of Microwave Transistors

F.N. Sechi, B.S. Perlman and J.M. Cusack. "Computer-Controlled Infrared Microscope for Thermal Analysis of Microwave Transistors." 1977 MTT-S International Microwave Symposium Digest 77.1 (1977 [MWSYM]): 143-146.

A new technique for acquiring the temperature profile of microwave power transistors by infrared scanning has been developed. It provides for emissivity calibration using an infrared microscope interfaced with a computer.

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